

USB DUAL STACKED A TYPE RECEPTACLE6

1.0 SCOPE

This Specification Covers the USB series product

2.0 PRODUCT DESCRIPTION

The following parts were used in the testing described in this document.

2.1 PRODUCT NAME AND PART NUMBER (S)

Part Numbers	Product Name
67298- 309*	USB CONNECTOR
67298- 409*	USB CONNECTOR

2.2 DIMENSIONS, MATERIALS, PLATINGS AND MARKINGS

Refer to Sales Drawing No.SD-67298-008;

2.3 PRODUCT SPECIFICATION TITLE AND DOCUMENT NUMBER

TITLE: USB CONNECTOR

Document Number: PS-67298-001

3.0 APPLICABLE DOCUMENTS AND SPECIFICATIONS

TESTING PROCEDURES AND SEQUENCES

Testing is performed sequentially in product specification number "PS-67298-001", Section A.

OTHER DOCUMENTS AND SPECIFICATIONS

EIA-364 Electrical Connector/Socket Test Procedures including Environmental Classification MIL-STD-1344 Test Method for Electrical Connectors (Military Standard)

4.0 QUALIFICATION

Laboratory conditions and sample selection are in accordance with EIA-364.

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A <u>EC No:</u> SH2005-0297		USB DUAL ST	1 of 4		
	<u>DATE:</u> 2003/04/20				1 01 1
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5.0 PERFORMANCE

5.1 ELECTRICAL PERFORMANCE RESULTS

ITEM	DESCRIPTION	TREATMENT	REQUIREMENT	MEAN	MINIMUM	MAXIMUM
	Initial	30 milliohms MAXIMUM	10.8mΩ	$5.8 m\Omega$	17.8mΩ	
		After Durability	30 milliohms MAXIMUM	15.2mΩ	8.1mΩ	20.9mΩ
		After Vibration	30 milliohms MAXIMUM	12.5mΩ	$6.3 m\Omega$	16.9mΩ
			No Discontinuity	Discontinu	ity < 1 micr	osecond
	Contact	After Shock (Mechanical)	30 milliohms MAXIMUM	10.6mΩ	5.9mΩ	20.5mΩ
1	Resistance		No Discontinuity	Discontinuit	y < 1 micros	second
	(Low Level)	After Shock (Thermal)	30 milliohms MAXIMUM	12.7mΩ	6.4mΩ	19.8mΩ
			No Damage	No Visual or Dimensional Change		
		After Thermal Aging	30 milliohms MAXIMUM	14.6mΩ	$7.2 m\Omega$	18.6mΩ
			No Damage	No Visual o	r Dimension	al Change
		After Humidity 1(Steady State)	30 milliohms MAXIMUM	12.4mΩ	6.5mΩ	22.7mΩ
			No Damage	No Visual o	r Dimension	al Change
	la sulstis s	Initial	1000 Meg ohms MINIMUM	angle 1000 Meg ohms		ims
2	Insulation Resistance	After Humidity (Steady State)	500 Volts DC MINIMUM	PASS		
			No Damage	No Visual or Dimensional Change		
		Initial	750 Volts AC MINIMUM	PASS		
_	Dielectric		No Damage	No Visual or Dimensional Change		
3	Withstanding Voltage	After Humidity (Steady State)	750 Volts AC MINIMUM	PASS		
			No Damage	No Visual or Dimensional Change		
4	Capacitance	Initial	2picofarad MAXIMUM		<2picofara	d
5	Temperature Rise	Final	+30 °C MAXIMUM RISE	9.0°C	8.9°C	9.3°C

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5.2 MECHANICAL PERFORMANCE RESULTS

ITEM	DESCRIPTION	TREATMENT	REQUIREMENT	MEAN	MINIMUM	MAXIMUM	
6 Connector Mate and Un-mate Force		Initial Insertion	3.57Kg MAXIMUM	1.52Kg	1.16Kg	1.71Kg	
	Initial un-mating	1.02Kg MINIMUM	2.05Kg	1.86Kg	2.53Kg		
7	Terminal Retention Force	Individual	0.8Kg MINIMUM	1.20Kg	1.15Kg	1.29Kg	
8	Durability	See ITEM 1 [TREATI	See ITEM 1 [TREATMENT: After Durability]				
9	Vibration (Random)	See ITEM 1 [TREATMENT: After Vibration]					
10	Shock (Mechanical)	See ITEM 1 [TREATMENT: After Shock(Mechanical)]					

5.3 ENVIRONMENTAL PERFORMANCE RESULTS

ITEM	DESCRIPTION	TREATMENT	REQUIREMENT			
11	Shock (Thermal)	ee ITEM 1 [TREATMENT: After Shock(Thermal)]				
12	Thermal Aging	See ITEM 1 [TREATMENT	e ITEM 1 [TREATMENT: After Thermal Aging]			
13	Humidity (Steady State)	See ITEM 1 [TREATMENT: After Humidity (Steady State)]				
14	Solder ability	Final	95% Coverage MINIMUM	Coverage > 95%		
15	Solder Resistance	Final	No damage	No Visual or Dimensional Change		

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6.0 FIXTURES AND TEST EQUIPMENT

ITEM	DESCRIPTIOM	MANUFACTURING	MODEL
1	Milliohm Meter	GW	GOM-801G
2	Withstanding Voltage/insulation Analyzer	GW	GPI-735
3	Automatic mat and unmated test equipment	AIKOH	AIKOH MODEL-1310N
4	DC POWER SUPPLY	GW	GPS-3030D
5	TEMPERATURE TESTER	KSON	THS-D4C-150
6	SHOCK TESTER	KSON	TSK-D4C-150
7	OVEN TESTER	ETQI	9721
8	VIBRATION TEST SYSTEM	UD	AS15-S452/ST

7.0 OTHER INFORMATION

The samples meet the product specification.

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